

Search Notes

Application/Control No.

10/765,565

Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	1/17/2007	DX
455	414.1	1/17/2007	DX

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass Search	1/17/2006	AX
Combined Text search	1/17/2006	CH